

Notice of References Cited	Application/Control No. 10/577,325		Applicant(s)/Patent Under Reexamination NAKAMURA ET AL.	
	Examiner MATTHEW W. SUCH		Art Unit 2891	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,720,572	04-2004	Jackson et al.	257/40
*	C	US-6,420,057	07-2002	Ueda et al.	428/690
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	K	US-			
	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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*	U	Klauk, H., et al. "Contact Resistance in Organic Thin Film Transistors." SOLID-STATE ELECTRONICS, Vol. 47 (2003): pp. 297-301.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.